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SEP 26 2006

PTO/SB/08a/b (08-03)
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Substitute for form 1449A/B/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

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of

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Complete If Known	
Application Number	10/672,961 (Conf. No. 9439)
Filing Date	September 26, 2003
First Named Inventor	Glenn J. Leedy
Art Unit	2822
Examiner Name	Monica Lewis
Attorney Docket Number	ELM-2 Cont. 4

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
MJ		US 3,636,358	01/18/1972	Groschwitz	
		US 3,932,932	01/20/1976	Goodman	
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Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ² -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		DE3233193	03-17-1983	Mitsubishi Electric Corp.		
		JP2037655	02-07-1990	Siemens AG		
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Examiner Signature	<i>Call</i>	Date Considered	11/10/07
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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		Wolf, Stanley and Richard N. Tauber; <u>Silicon Processing For the VLSI Era, Volume 1: Process Technology</u> ; Sunset Beach, CA: Lattice Press, 1986, pages 191-194	
		European Search Report for Application No. EP 02 00 9643 (date completed: October 8, 2002)	
		Phys. Rev. B., Condens. Matter Mater. Phys. (USA). Physical Review B (Condensed Matter and Materials Physics), 15 March 2003, APS through AIP, USA.	
		S. Wolf, <u>Silicon Processing For the VLSI Era</u> , 1990, Lattice Press, Volume 2, page 191.	
		Svechnikov, S.V.; Kobylavskaya, M.F.; Kimarskii, V.I.; Kaufman, A.P.; Kuzolev, Yu. I.; Cherepov, Ye. I.; Fomin, B.I.; "A switching plate with aluminium membrane crossings of conductors"; 1972	
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